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BIBDATASHEET

Bib Data Sheet

CONFIRMATION NO. 8874

SERIAL NUMBER 09/891,611	FILING DATE 06/27/2001 RULE	C	LASS 250	GROUP ART L 2881	INII	TTORNEY OCKET NO. 010817	
APPLICANTS							
Mamoru Nakasuji, Kanagawa, JAPAN;							
Nobuharu Noji, Kanagawa, JAPAN; Tohru Satake, Kanagawa, JAPAN;Toshifumi Kimba, Kanagawa, JAPAN; Hirosi Sobukawa, Kanagawa, JAPAN; Shoji Yoshikawa, Tokyo, JAPAN; Tsutomu Karimata, Kanagawa, JAPAN; Shin Oowada, Kanagawa, JAPAN; Mutsumi Saito, Kanagawa, JAPAN; Muneki Hamashima, Chiba, JAPAN; Toru Takagi, Kanagawa, JAPAN;							
CONTINUING DATA							
** FOREIGN APPLICATIONS ************************************							
JAPAN 192918/2000 06/27/2000 JAPAN 335751/2000 11/02/2000 JAPAN 336156/2000 11/02/2000 JAPAN 335752/2000 11/02/2000 JAPAN 2000-336091 11/02/2000 JAPAN 2000-337058 11/06/2000 JAPAN 2000-377285 12/12/2000 JAPAN 2001-031901 02/08/2001 JAPAN 2001-031906 02/08/2001 JAPAN 2001-033599 02/09/2001 JAPAN 2001-112745 04/11/2001 JAPAN 2001-115060 04/13/2001 JAPAN 2001-115060 04/13/2001 JAPAN 2001-158571 05/28/2001 F REQUIRED, FOREIGN FILING LICENSE GRANTED							
** 08/23/2001		Maraban en		~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	**************************************	<u>,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,</u>	
Foreign Priority claimed 35 USC 119 (a-d) conditions met	yes no Met after		STATE OR	SHEETS	TOTAL	INDEPENDENT	
Verified and Acknowledged Ex	75.40 11 WOLLAND	ojtřáls	COUNTRY	DRAWING 60	CLAIMS 1	CLAIMS 1	

ADDRESS 23850 ARMSTRONG, F 1725 K STREET SUITE 1000 WASHINGTON 20006	•			
TITLE Inspection syster	n by charged particle beam and method of manufacturing	devices using the system		
		☐ All Fees		
		☐ 1.16 Fees (Filing)		
	FEES: Authority has been given in Paper No to charge/credit DEPOSIT ACCOUNT	☐ 1.17 Fees (Processing Ext. of time)		
RECEIVED 7400	No for following:	☐ 1.18 Fees (Issue) ☐ Other		
		☐ Credit		